

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
		Examiner Chuong A. Luu	Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,304,357	04-1994	Sato et al.	118/50.1
	B	US-			
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	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP2001-044120	02-2001	Japan	Tetsuya et al.	
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	R					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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